

Accepted Manuscript

Critical thickness phenomenon in single-crystalline wires under torsion

Dabiao Liu, Xu Zhang, Yuan Li, D.J. Dunstan

PII: S1359-6454(18)30207-6

DOI: [10.1016/j.actamat.2018.03.022](https://doi.org/10.1016/j.actamat.2018.03.022)

Reference: AM 14442

To appear in: *Acta Materialia*

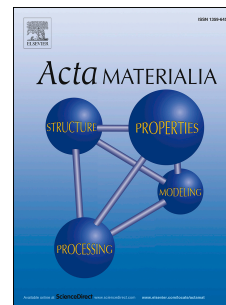
Received Date: 5 December 2017

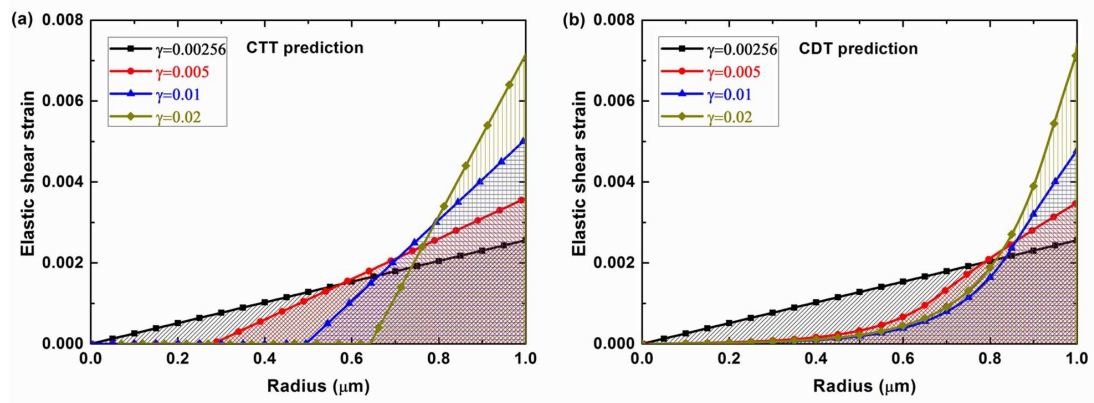
Revised Date: 19 February 2018

Accepted Date: 11 March 2018

Please cite this article as: D. Liu, X. Zhang, Y. Li, D.J. Dunstan, Critical thickness phenomenon in single-crystalline wires under torsion, *Acta Materialia* (2018), doi: 10.1016/j.actamat.2018.03.022.

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